

IEC QUALITY ASSESSMENT SYSTEM (IECQ)

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Schedule of Scope to Certificate of Approval

Independent Testing Laboratory

IECQ Certificate No.: IECQ-L CEP 24.0001 CB Certificate No.: IECQ-L 2024.006

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№	Products, Materials	Items,Parameter		Title, Code of specification, standard or method
		№	Items,Parameter	used
1	Electrical and electronic products/ electronic semiconductor products	1	Visual inspection of appearance	Test methods and procedures for microelectronic devices GJB-548C-2021 Method 2009.2
		2	Decap	Methods for destructive physical analysis of military electronic components GJB-4027B-2021 in 1103 in 2.6.2
		3	SEM Inspection	Test methods and procedures for microelectronic devices GJB-548C-2021 Method 2018.2
		4	Delayer	Test Methods and Procedures for Microelectronic Devices GJB-548C-2021 Method 5003 in 3.3.3
		5	IV CURVE	Test methods and procedures for microelectronic devices GJB-548C-2021 Method 5003 in 3.2.3.3.2.4
		6	InGaAs/OBIRCH	Test methods and procedures for microelectronic devices GJB-548C-2021 Method 5003 in 3.4(d)
		7	Cross-section Polish	Test methods and procedures for microelectronic devices GJB-548C-2021 method 5003 in 3.3.2
		8	Probe Test	Test Methods and Procedures for Microelectronic Devices GJB-548C-2021 Method 5003 in 3.2.12
		9	EDS Analysis	Test methods and procedures for microelectronic devices GJB-548C-2021 Method 5003 in 3.4.e

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